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The First IEEE International Workshop on Electronic Design, Test and Applications (DELTA 2002)

Michel Renovell, Seiji Kajihara, Ibrahim Ai-Bahadly, Serge Demidenko

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Proceedings

The First IEEE International Workshop on
Electronic Design, Test and Applications



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Electronic Design, Test and Applications


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M. Renovell, S. Kajihara, I. Al-Bahadly and S. Demidenko

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Table of Contents

Committees	xiii
Reviewers	xv
Message from the General Co-Chairs	xvi
Message from the Program Co-Chairs	xvii

Technical Sessions

Analog Test

Analog and Mixed-Signal IP Cores Testing	3
<i>M. W. T. Wong, K.Y. Ko, and Y.S. Lee</i>	
Testable Design and Testing of High-Speed Superconductor Microelectronics	8
<i>H. G. Kerkhoff, A. A. Joseph, and S. Heuvelmans</i>	
Observer-Based Test of Analog Linear Time-Invariant Circuits	13
<i>Z. Guo and J. Savir</i>	
Practical Oscillation-Based Test in Analog Integrated Filters: Experimental Results	18
<i>G. Huertas, D. Vazquez, A. Rueda, and J. L. Huertas</i>	
Constrained Specification-Based Test Stimulus Generation for Analog Circuits Using Nonlinear Performance Prediction Models	25
<i>S. Bhattacharya and A. Chatterjee</i>	

Communications

MIMO Transmit Optimization for Wireless Communication Systems	33
<i>R. Choi and R. Murch</i>	
Adaptive Power Control Design for Microwave Communication System	38
<i>T. A. Rahman and T. C. Leng</i>	
VSIA Interface Cosynthesis	43
<i>S. Ouadjaout, M.-F. Albenge, and D. Houzet</i>	
Bluetooth-Based Wireless Personal Area Network for Multimedia Communication	47
<i>J. Y. Khan, J. Wall, and M. A. Rashid</i>	
Multi-User Detection for CDMA Communications Based on Self Organized Neural Networks Structures	52
<i>F. Carlier, F. Nouvel, and J. Citerne</i>	

Digital Signal Processing and Architectures

An Applications-Based Approach to Measuring DSP Efficiency.....	59
<i>J. G. Chase, C. Pretty, A. Bedarida, and P. Bettler</i>	
Reconfigurable DSP's for Efficient MPEG-4 Video and Audio Decoding.....	63
<i>C. Pretty and J. G. Chase</i>	
Smart Antenna Software Radio Test System	68
<i>P. J. Green and D. P. Taylor</i>	
GALA Approach in Design of Asynchronous Control for Counterflow Pipeline Processor.....	73
<i>V. Varshavsky and V. Marakhovsky</i>	

From Low to High Level Fault Simulation and Diagnosis

Behavioral Fault Simulation: Implementation and Experiments Results	81
<i>D. Federici, P. Bisgambiglia, and J.-F. Santucci</i>	
Multi-Level Fault Simulation of Digital Systems on Decision Diagrams	86
<i>R. Ubar, J. Raik, E. Ivask, and M. Brik</i>	
Fault Simulation Method for Crosstalk Faults in Clock-Delayed Domino CMOS Circuits	92
<i>K. Shimizu, M. Takamura, T. Shirai, N. Itazaki, and K. Kinoshita</i>	

High Level Design

Research on VHDL RTL Synthesis System	99
<i>H. Zhou, Z. Lin, and W. Cao</i>	
An Accurate Coverage Forecasting Model for Behavioral Model Verification	104
<i>A. Hajjar and T. Chen</i>	
A Novel CAM/RAM Based Buffer Manager for Next Generation IP Routers	111
<i>C. Dou, S.-J. Jiang, and K.-C. Leu</i>	
Interconnect IP Node for Future System-on-Chip Designs	116
<i>I. Saastamoinen, D. Sigüenza-Tortosa, and J. Nurmi</i>	

Memory

Signal Margin Analysis for Memory Sense Amplifiers.....	123
<i>J. Vollrath</i>	
Address and Data Scrambling: Causes and Impact on Memory Tests	128
<i>A. J. van de Goor and I. Schanstra</i>	
Flash Memory Built-In Self-Test Using March-Like Algorithms.....	137
<i>J.-C. Yeh, C.-F. Wu, K.-L. Cheng, Y.-F. Chou, C.-T. Huang, and C.-W. Wu</i>	
A Method for Storing Fail Bit Maps in Burn-In Memory Testers.....	142
<i>A. Iseno and Y. Iguchi</i>	

Power Issues in Design and Test

Coup de Fouet Based VRLA Battery Capacity Estimation	149
<i>P. E. Pascoe, H. Sirisena, and A. H. Anbuky</i>	
Power Optimization of Combinational Circuits by Input Transformations	154
<i>C. Gopalakrishnan and S. Katkooi</i>	
Reducing Test Power During Test Using Programmable Scan Chain Disable	159
<i>R. Sankaralingam and N. A. Toubia</i>	

Sensor and Analog Design

Test Socket Chip for Measuring Dark Current in IR FPA	167
<i>M. L. Sheu, T. P. Sun, and F.-W. Jih</i>	
A Low Power High Speed Class-B Buffer Amplifier for Flat Panel Display Application	172
<i>C.-W. Lu and C. L. Lee</i>	
Design of a Low-Voltage Instrumentation Amplifier for Enzyme-Extended-Gate Field Effect Transistor Based Urea Sensor Application	177
<i>W.-Y. Chung, M.-H. Yeh, J.-C. Chen, S.-K. Hsiung, D. G. Pijanowska, W. Torbicz, J.-C. Chou, and T.-P. Sun</i>	
A Silicon Piezoresistive Pressure Sensor	181
<i>R. Singh, L. L. Ngo, H. S. Seng, and F. N. C. Mok</i>	

Special Session on Education

Evolution of the MOSIS VLSI Educational Program	187
<i>C. A. Piña</i>	
The Search for Design in Electrical Engineering Education	192
<i>D. V. Kerns, S. E. Kerns, G. A. Pratt, M. H. Somerville, and J. D. Crisman</i>	
The Development and Transfer of Advanced Technology from Universities to Industry	197
<i>R. M. Hodgson</i>	
Competencies of BSc and MSc Programmes in Electrical Engineering and Student Portfolios	203
<i>T. J. Mouthaan, R.W. Brink, and H. Vos</i>	
Electronics Education: A Systems Based Mechatronic Approach	209
<i>D. A. Carnegie</i>	
Boundary Scan as a Test Solution in Microelectronics Curricula	214
<i>A. Rucinski and B. Dziurla-Rucinska</i>	
Making ATE Accessible for Academic Institutions	219
<i>W. Moorhead and S. Demidenko</i>	
Teaching Integrated Circuit and Semiconductor Device Design in New Zealand: The University of Canterbury Approach	223
<i>R. J. Blaikie, M. M. Alkaisi, S. M. Durbin, and D. R. S. Cumming</i>	

European Network for Test Education.....	230
<i>Y. Bertrand, M.-L. Flottes, F. Azaïs, S. Bernard, L. Latorre, and R. Lorival</i>	
PARTOS-11: An Efficient Real-Time Operating System for Low-Cost Microcontrollers.....	235
<i>Y. Li and P. Wilson</i>	
Design of a Processor to Support the Teaching of Computer Systems	240
<i>M. Pearson, D. Armstrong, and T. McGregor</i>	
Applied Science (Electronics) at the University of Otago	245
<i>J. L. Bähr</i>	
Harnessing Geographically Distributed Cooperation in Microtechnology Course at Massey University	250
<i>R. Browne, S. Demidenko, and R. O'Driscoll</i>	
Special Session on Electromagnetics and Control	
Design of an Auxiliary Power Distribution Network for an Electric Vehicle	257
<i>W. Chen, S. Round, and R. Duke</i>	
Analysis of Position Estimation Method for Switched Reluctance Drives	262
<i>I. H. Al-Bahadly</i>	
Conceptual Design of an All Superconducting Mini Power Plant Model	267
<i>I. Vajda</i>	
Magnetic Hysteresis Modeling of Electronic Components	272
<i>H. Hauser, P. Fulmek, F. Himmelstoss, T. Wolbank, R. Wöhrnschimmel, and P. Wurm</i>	
Computer Based Real-Time Simulator for Renewable Energy Converters	280
<i>D. Parker</i>	
Special Session on FPGA	
On Biologically-Inspired Design of Fault-Tolerant Digital Systems.....	287
<i>P. K. Lala and K. K. Bondali</i>	
On-Line Diagnosis and Reconfiguration of FPGA Systems	291
<i>A. Antola, V. Piuri, and M. Sami</i>	
Testing the Unidimensional Interconnect Architecture of Symmetrical SRAM-Based FPGA.....	297
<i>M. Renovell, P. Faure, P. Prinetto, and Y. Zorian</i>	
A Fault-Tolerant FPGA-Based Multi-Stage Interconnection Network for Space Applications	302
<i>M. Alderighi, F. Casini, S. D'Angelo, D. Salvi, and G. R. Sechi</i>	

Special Session on Image Processing

FPGA-Based Implementation of Variable Sized Structuring Elements for 2D Binary Morphological Operations	309
<i>J. Velten and A. Kummert</i>	
FPGA Implementation of a Neural Network for a Real-Time Hand Tracking System	313
<i>M. Krips, T. Lammert, and A. Kummert</i>	
Neural Networks to Solve the Problems of Control and Identification.....	318
<i>S. Demidenko, R. K. Sadykhov, L. P. Podenok, M. E. Vatkin, and A. N. Klimovich</i>	
On the Initialization and Training Methods for Kohonen Self-Organizing Feature Maps in Color Image Quantization	321
<i>X. Rui, C.-H. Chang, and T. Srikanthan</i>	
An Architecture for High Speed Ultrasound Image Capture and Real-Time 3D Reconstruction	326
<i>S. Sanei and T. K. M. Lee</i>	

Special Session on Robotics

Genetic Algorithm Application to Vibration Control of Tall Flexible Structures	333
<i>S. Kundu, K. Seto, and S. Sugino</i>	
State Transition Based Supervisory Control for a Robot Soccer System	338
<i>G. Sen Gupta, C. H. Messom and H. L. Sng</i>	
A Semi-Generic System for the Control of Autonomous Mobile Mechatrons	343
<i>D. A. Carnegie</i>	
Strategy for Collaboration in Robot Soccer	347
<i>H. L. Sng, G. Sen Gupta, and C. H. Messom</i>	

Special Session on Submicron Technology

A Novel Analytical Model for Evaluation of Substrate Crosstalk in VLSI Circuits	355
<i>N. Masoumi, M. I. Elmasry, S. Safavi-Naeini, and H. Hadi</i>	
A Comprehensive Fault Model for Deep Submicron Digital Circuits	360
<i>J. A. Abraham, A. Krishnamachary, and R. S. Tupuri</i>	
Noise Analysis under Capacitive and Inductive Coupling for High Speed Circuits	365
<i>S. H. Choi and K. Roy</i>	
Noise—Its Sources, and Impact on Design and Test of Mixed Signal Circuits	370
<i>M. d'Abreu</i>	

Test Generation and Compaction

Properties of Output Sequences and Their Use in Guiding Property-Based Test Generation for Synchronous Sequential Circuits	377
<i>I. Pomeranz and S. M. Reddy</i>	
Path-Oriented Test Data Generation of Behavioral VHDL Description	382
<i>C. Paoli, M.-L. Nivet, J.-F. Santucci, and A. Campana</i>	
Random Pattern Testability of the Open Defect Detection Method Using Application of Time-Variable Electric Field	387
<i>H. Yotsuyanagi, M. Hashizume, T. Iwakiri, M. Ichimiya, and T. Tamesada</i>	
A Method of Static Test Compaction Based on Don't Care Identification	392
<i>K. Miyase, S. Kajihara, and S. M. Reddy</i>	
Generating Small Test Sets for Test Compression / Decompression Scheme Using Statistical Coding	396
<i>H. Ichihara and T. Inoue</i>	

Test Techniques and Methodologies

I _{DDT} Test Methodologies for Very Deep Sub-Micron CMOS Circuits	403
<i>A. Chehab, R. Makki, M. Spica, and D. Wu</i>	
A Functional Approach to Test Cascaded BCD Counters	408
<i>G. Peretti, E. Romero, F. Salvático, and C. Marqués</i>	
Test Data Compression Using Don't-Care Identification and Statistical Encoding	413
<i>S. Kajihara, K. Taniguchi, I. Pomeranz, and S. M. Reddy</i>	
On C-Testability of Carry Free Dividers	417
<i>S. M. Aziz and S. J. Carr</i>	

Poster Papers

Modeling of a Repulsive Type Magnetic Bearing for Five Axis Control under Intermittent Operation Including Eddy Current Effect	425
<i>S. C. Mukhopadhyay</i>	
A Novel Compound Type Resonant Rectifier Topology	428
<i>C. Chakraborty and S. C. Mukhopadhyay</i>	
Modifying Test Vectors for Reducing Power Dissipation in CMOS Circuits	431
<i>Y. Higami, S. Kobayashi, and Y. Takamatsu</i>	
Minimization and Partitioning Method Reducing Input Sets	434
<i>J. Hlavicka and P. Fiser</i>	
Stand-Alone Digital Real-Time Image Processing Board Based on an FPGA	437
<i>M. Pieper and A. Kummert</i>	
Transmission of Data/Sketch through Telephone Lines using Gapping Technique via a Low Cost Telewriting Equipment	440
<i>Z. B. K. Mastan, A. Ghazali, and M. M. Idris</i>	

Enhancing the Static D.C. Fault Diagnosis of a Resistance Temperature Detector Sensor Circuit Using Equivalent Fault Analysis	443
<i>M. Worsman, M. W. T. Wong, and Y. S. Lee</i>	
Test Power: A Big Issue in Large SOC Designs	447
<i>Y. Bonhomme, P. Girard, C. Landrault, and S. Pravossoudovitch</i>	
Multi-Carrier CDMA over Copper Lines—Comparison of Performances with the ADSL System	450
<i>S. Mallier, F. Nouvel, J.-Y. Baudais, D. Gardan, and A. Zeddani</i>	
Multivariable Predictive Feedback Control	453
<i>L. L. Giovanini</i>	
Power Supply Circuit for High Speed Operation of Adiabatic Dynamic CMOS Logic Circuits	459
<i>M. Hashizume, M. Sato, H. Yotsuyanagi, and T. Tamesada</i>	
Monitoring Parallel Interfaces in System Environment	462
<i>J. Sosnowski and K. Szafran</i>	
Pipelining Extended Givens Rotation RLS Adaptive Filters	466
<i>S. Tenqchen, J.-H. Chang, W.-S. Feng, and B.-S. Jeng</i>	
A Flexible Embedded SRAM Compiler	474
<i>Y. Liu, Z. Gao, and X. He</i>	
Advanced Instruction Set Architectures for Reducing Program Memory Usage in a DSP Processor	477
<i>P. Simonen, I. Saastamoinen, M. Kuulusa, and J. Nurmi</i>	
Sensorless Speed Control in Induction Motor Drives	480
<i>W. Phipps and I. Al-Bahadly</i>	
A High Voltage Amplifier for Use in Medical Applications of Electroporation	483
<i>P. Gaynor and J. Skipwith</i>	
A Simple Microcontroller Based Digital Lock-In Amplifier for the Detection of Low Level Optical Signals	486
<i>A. A. Dorrington and R. Künnemeyer</i>	
An Intelligent System for Odour Discrimination	489
<i>R. Singh</i>	
Test Chirp Signal Generation Using Spectral Warping	492
<i>W. Allen, D. Bailey, S. Demidenko, and V. Piuri</i>	
A New Transitive Closure Algorithm with Application to Redundancy Identification	496
<i>V. Gaur, V. D. Agrawal, and M. L. Bushnell</i>	
Test Bed for Number Plate Recognition Applications	501
<i>D. G. Bailey, D. Irecki, B. K. Lim, and L. Yang</i>	
A Synthesizable VHDL Model for an Easily Testable Generalised Multiplier	504
<i>S. M. Aziz, C. M. Basheer, and J. Kamruzzaman</i>	

A Comparison of Genetic Programming and Genetic Algorithms for Auto-Tuning Mobile Robot Motion Control	507
<i>M. Walker and C. H. Messom</i>	
Author Index	511
TTTC: Test Technology Technical Council	515